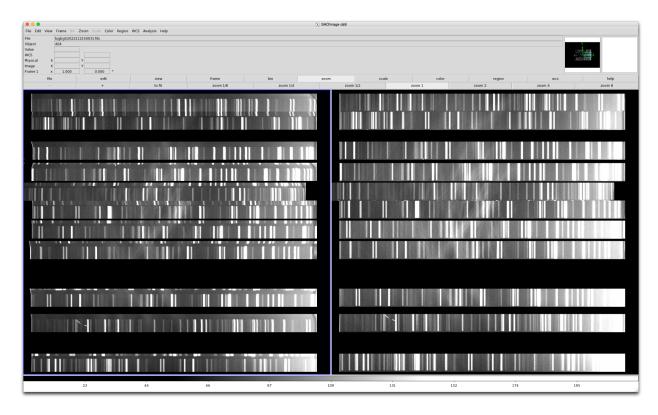
On MOS mdf adjustment

The Y-shift in the position of the detector after the recent troubleshooting has the effect of the MOS mask slits as defined *on the MDF* appearing with a small (~20 pix) yet systematic offset with respect to the actual location of the spectra.

As a result, when reducing MOS data (for data taken **after July 2022**), the individual extensions extractions (corresponding to individual slitlets) will look truncated. In the snapshot (left panel) you can see this effect on an arc frame. The arcs appear shifted 20 pix downward with respect to the extracted regions of interest. On the right panel, how should they look.



There are two ways of fixing this:

1) Adjusting the mdf with tcalc:

```
tcalc <mdf_file.fits> "slitpos_my" slitpos_my-2.0 colfmt="f6.2"
and running again the reduction, now the arcs are correctly extracted.
```

2) Adjusting the "yoffset" parameter in the task gsreduce (or gscut). Lower values will move the 'cuts' downward (subtracting 40 units worked in this particular case).